

<b>Notice of References Cited</b>	Application/Control No. 10/579,732		Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner JOSEPH DEAN, JR		Art Unit 4154	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0157936	08-2003	Ohtani et al.	455/436
*	C	US-2004/0137901	07-2004	Hamasaki et al.	455/436
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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